

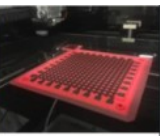
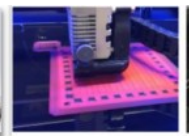
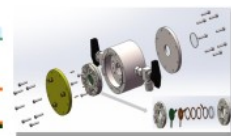
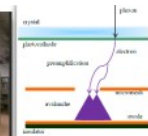
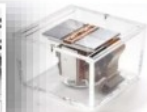
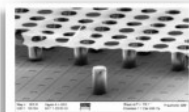
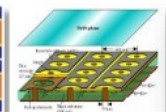
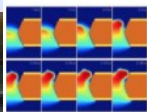
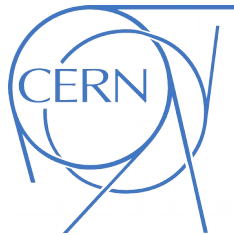
Recent results from the Resistive-CP group

Rate capability of μ -RWELL with X-ray

2021/02/09

Matteo Giovannetti
LNF-INFN

on behalf of the Resistive-CP group

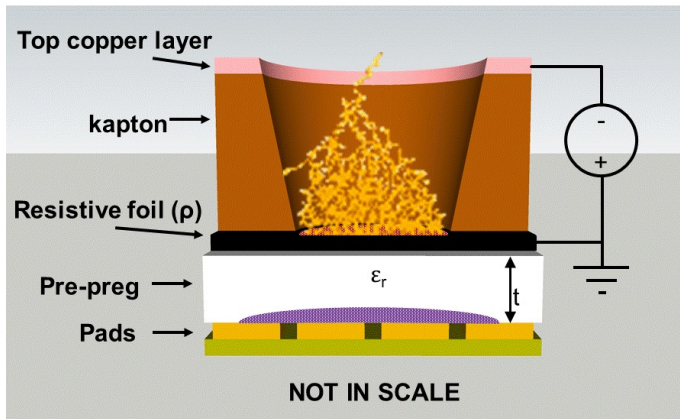


Outline

- X-ray PEDP rate capability results (Z. Yi)
- The LNF setup
- Results for different evacuation schemes
 - μ -RWELL (DRL, SG)
 - MicroMegs (DLC20, *M. Iodice*)
- Conclusions & future steps

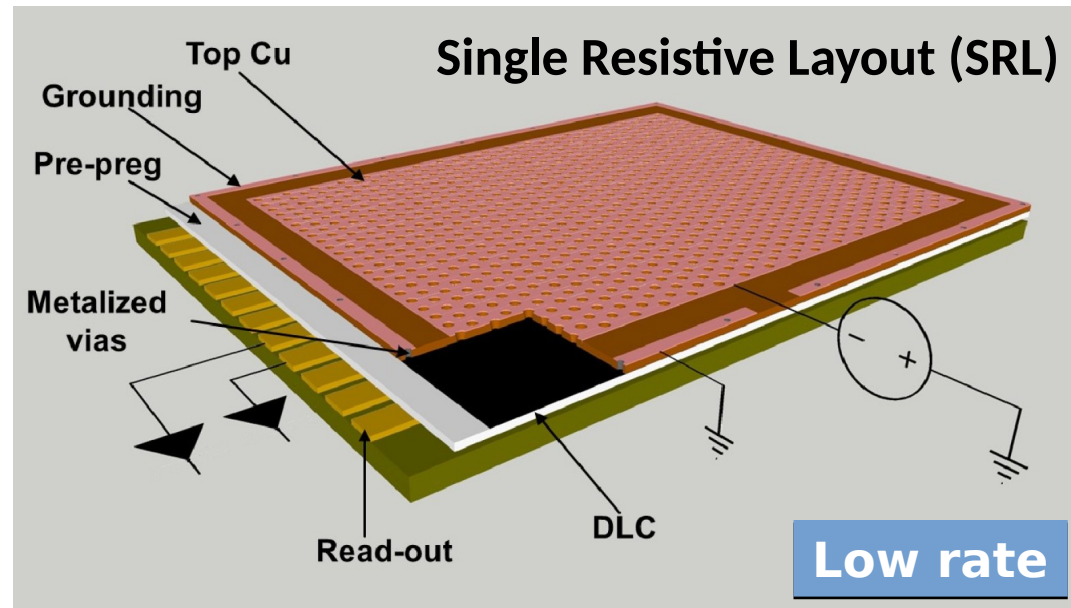
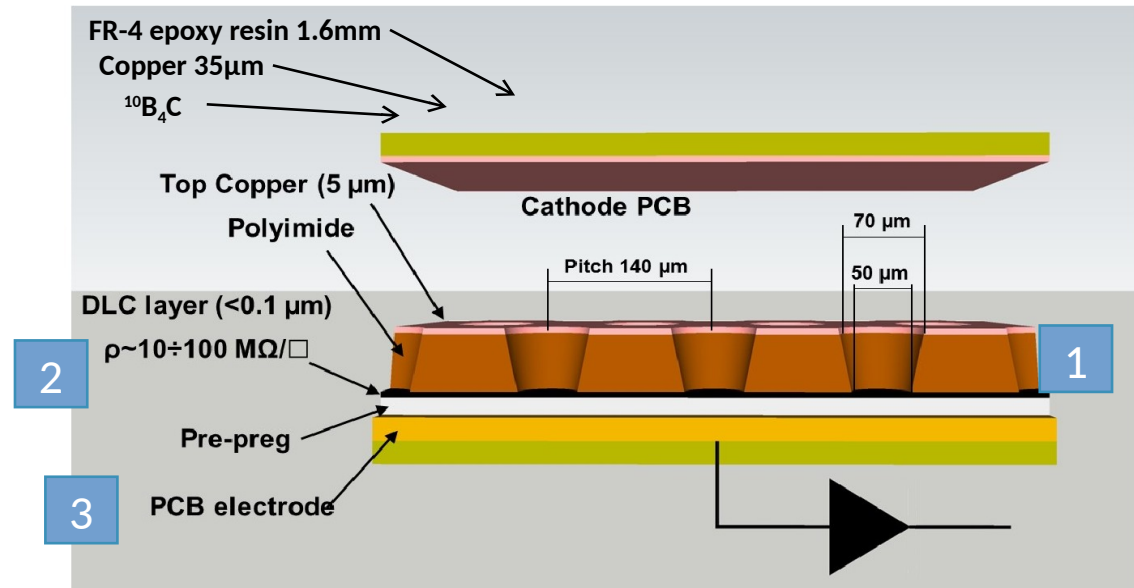
The μ -RWELL architecture

- 1 a **WELL** patterned Apical foil acting as **amplification stage** (GEM-like)
- 2 a **resistive DLC layer** for discharge suppression w/ surface resistivity $\sim 10 \div 200 \text{ M}\Omega/\square$
- 3 a standard readout PCB



Resistive stage:

- + spark suppression, charge spread
- rate capability reduction



X-ray PEDP ratecap results

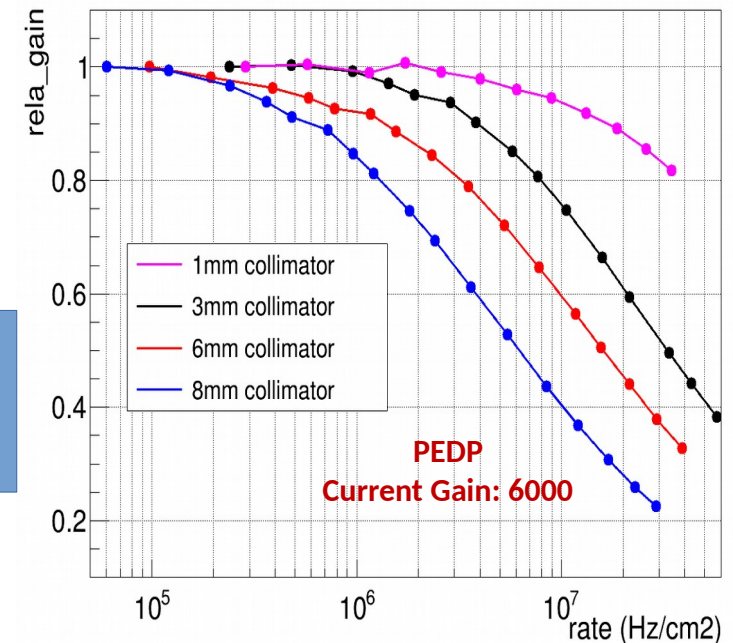
Effect noted by Zhou Yi with **X-rays**: for the new **PEDP** prototypes (pattern-etch-drill-plate) there is a **dependance of the rate capability on the spot size** (collimators from 1mm to 50mm diameter).



PEDP μ RWELL

Conductive hole pitch: 5 mm

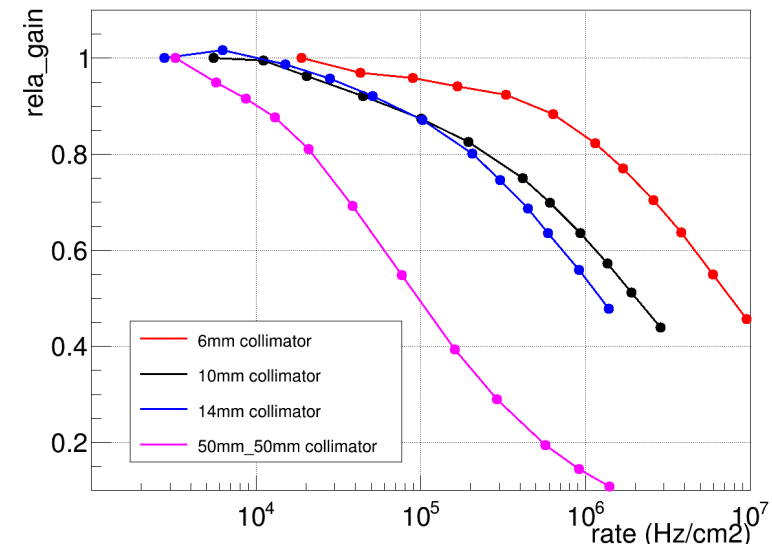
DOT-like
grounding
scheme



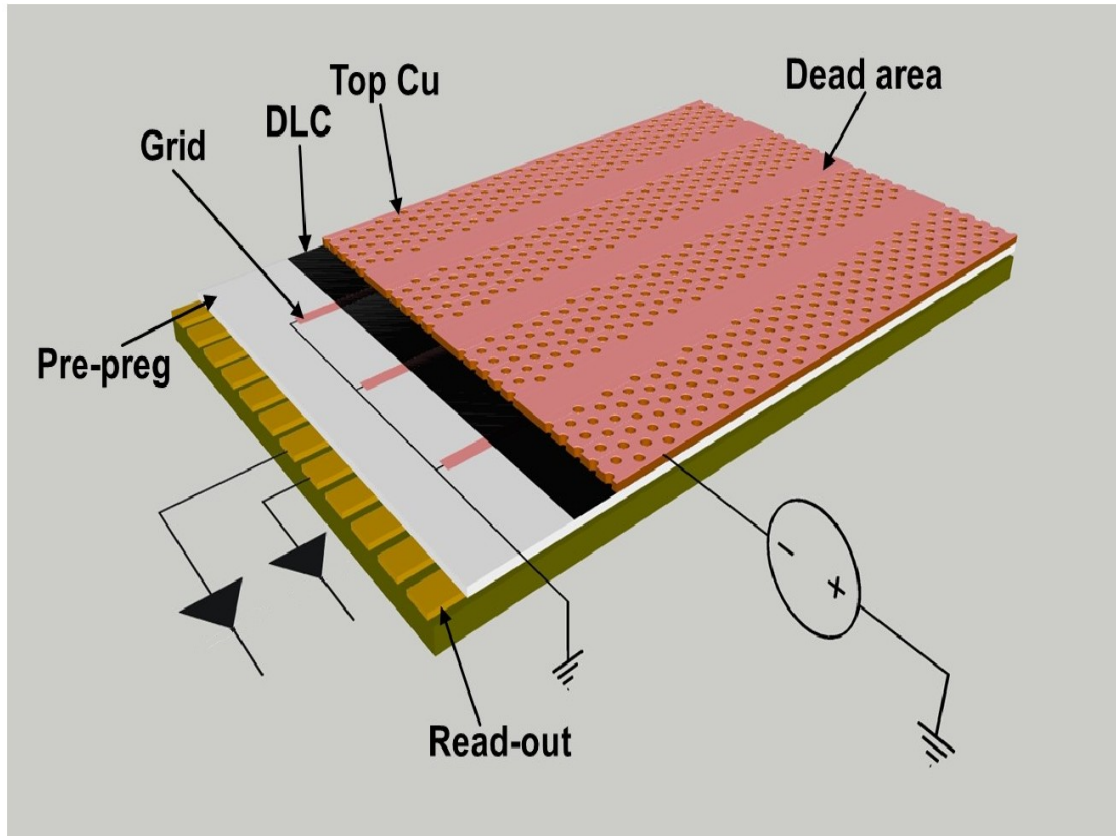
In order to understand this effect, Frascati starts the same test with different evacuation schemes: (DOT-like) DRL, DRL-buried (Grid-like) SG-1 and SG-2.

A comparison with MicroMegas has been also done.

Three parameters seem crucial for a comparison among the different technologies: **surface resistivity, ground pitch and spot size.**

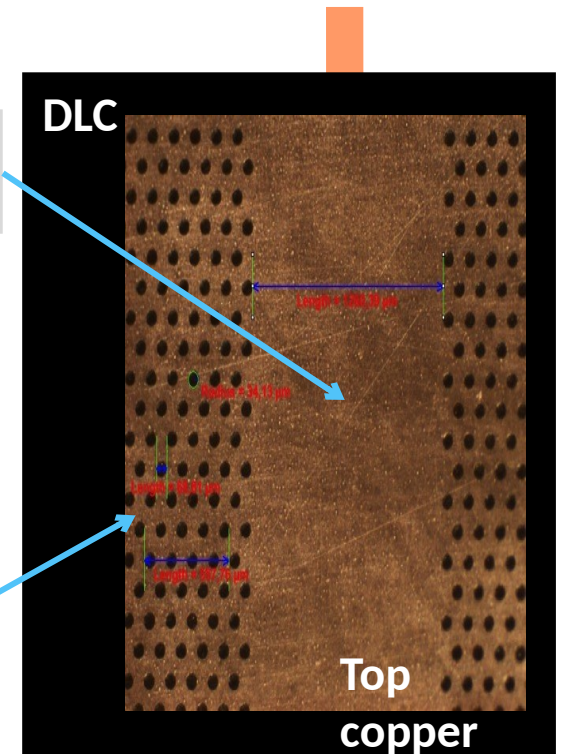


Silver Grid layout



1.2 mm
DEAD ZONE
(SG1)

70 μ m
WELL
diameter



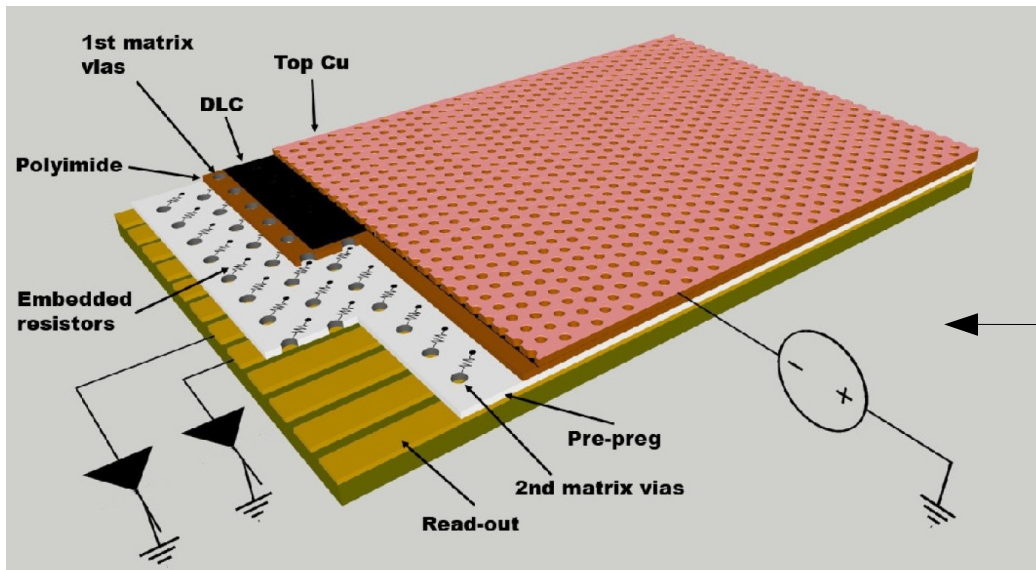
DLC layer (65 M Ω / \square)

GRID-like
grounding
scheme

MODEL	DEAD AREA (mm)	Ground pitch (mm)	Geom. Accept.
SG2++	0.6	12	95%
SG2	1.2	12	90%
SG1	2.0	6	66%

Conductive
Grid
under the DLC

Double Resistive Layers layout



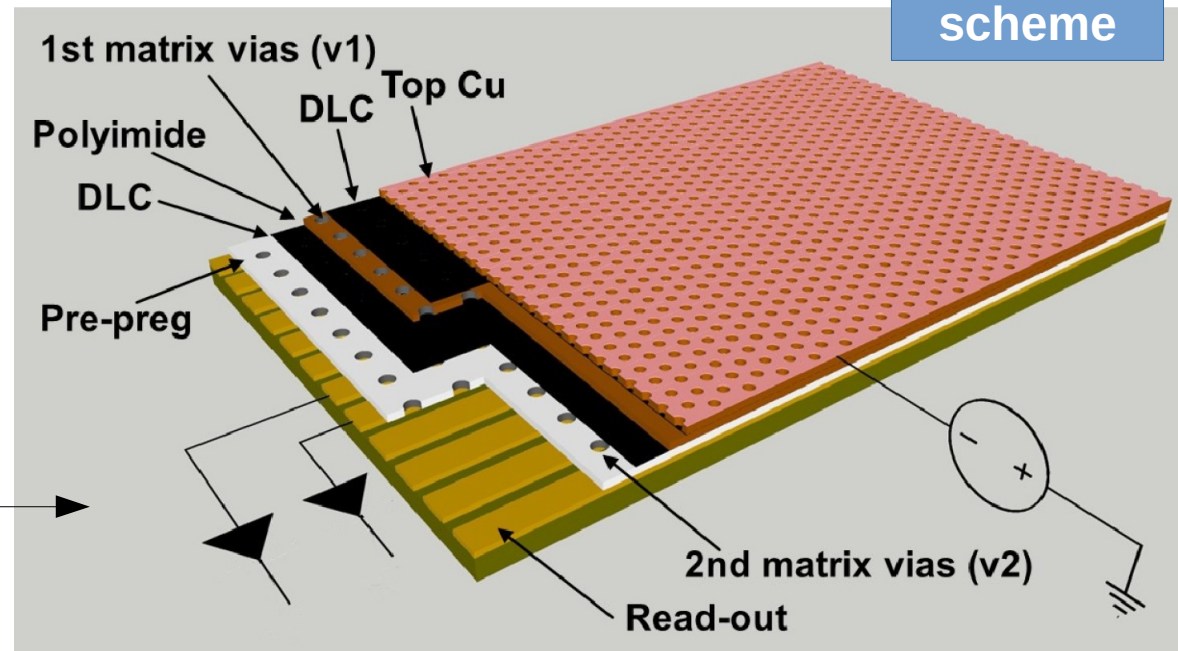
DRL-buried layout

DLC layer ($\sim 50 \text{ M}\Omega/\square$), 1cm pitch vias matrix, grounded through screen printed resistors ($1 \text{ M}\Omega$) to the readout.

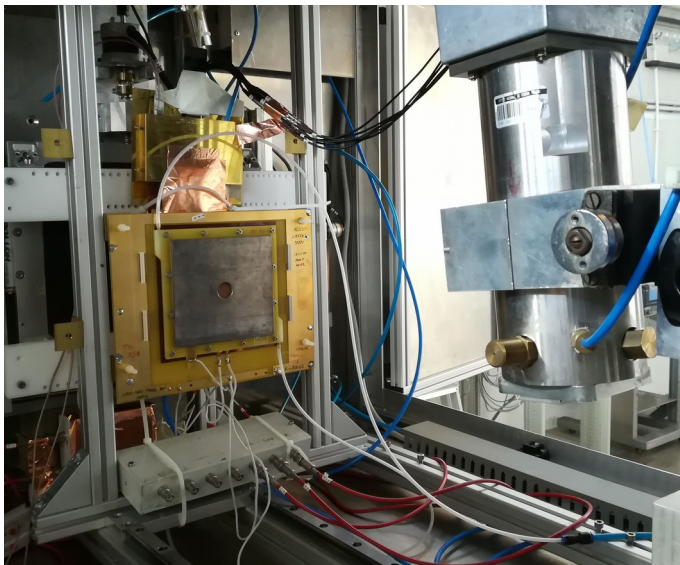
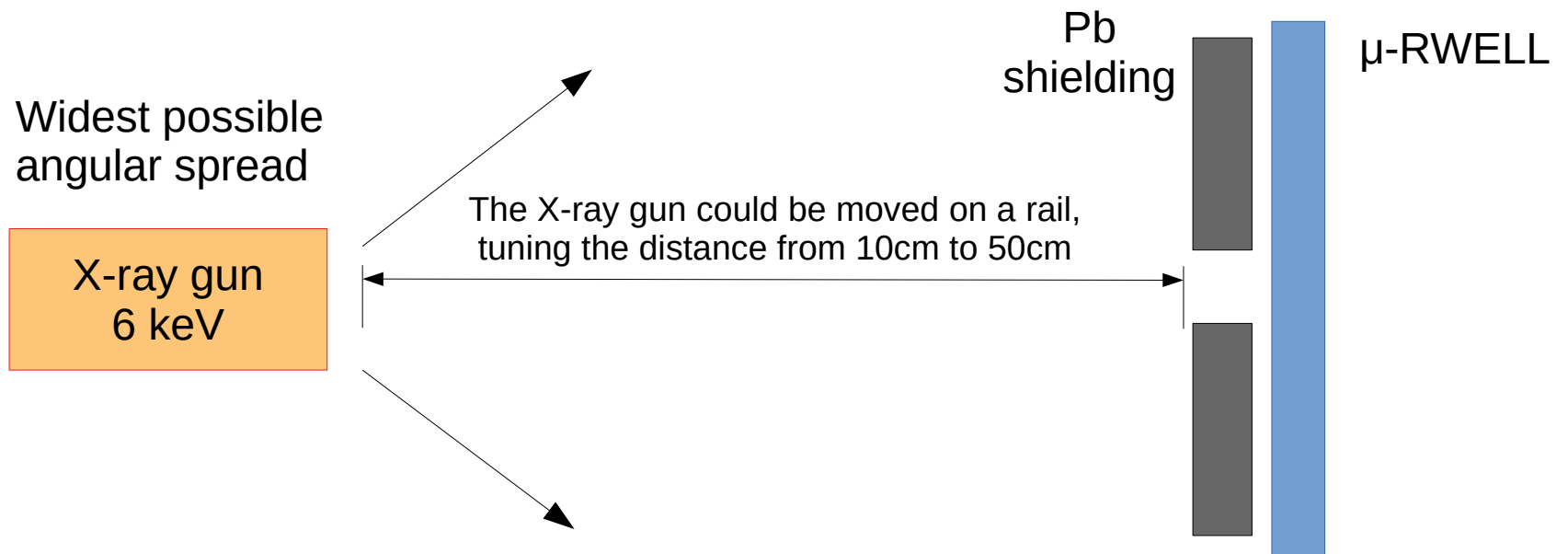
DOT-like
grounding
scheme

DRL layout

Two DLC layers ($54 \text{ M}\Omega/\square$), connected between them with a 7mm pitch vias matrix, and then grounded to the readout.



X-ray measurements setup

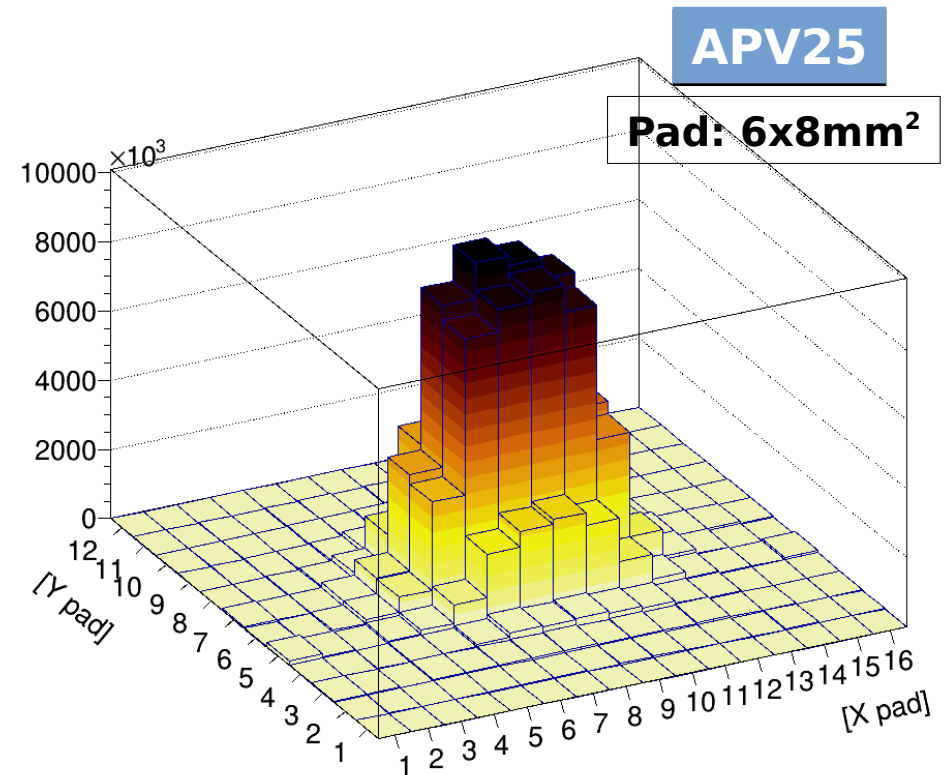
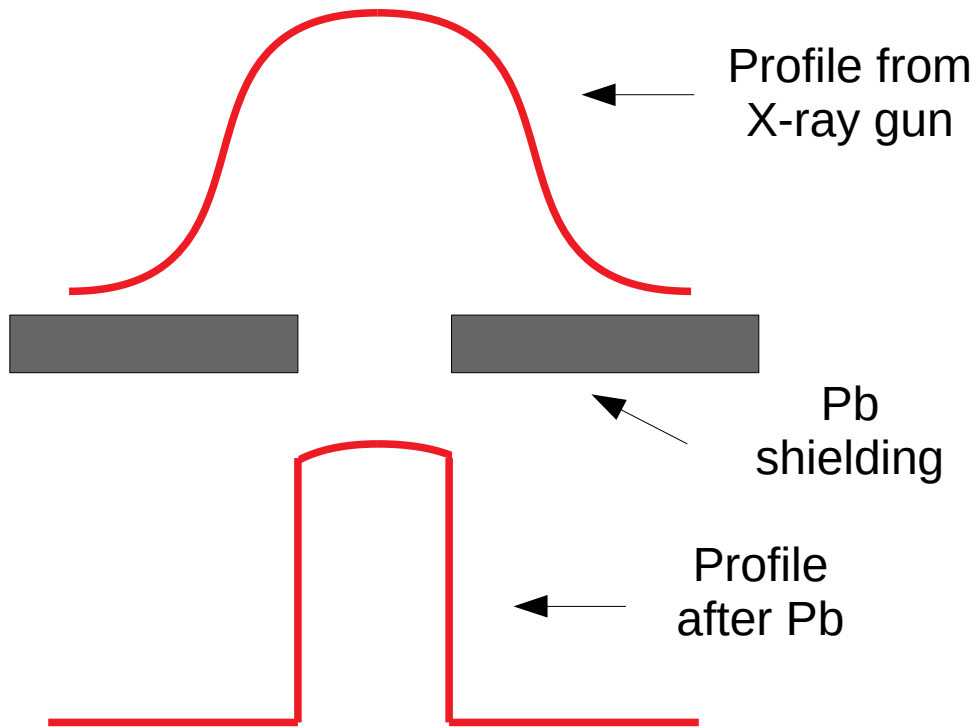


The **Pb shielding** is larger than the active area of the detector, with a **circular hole** in the center. We chose 20, 30 and 40mm \varnothing (see next slide), larger than the grounding pitch.

$X_0(\text{Pb}) = 2\mu\text{m}$ \rightarrow we use a **1mm thick Pb foil** to ensure the total shielding.

Heavy cathode (1.6mm FR4 + 35 μm Cu): measured attenuation factor x50 \rightarrow 98% of the X-ray absorbed.

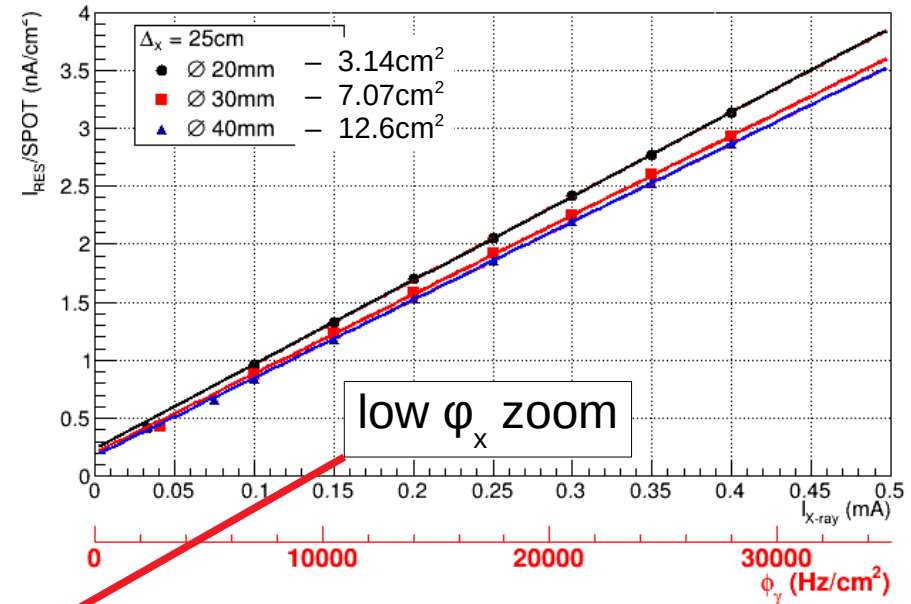
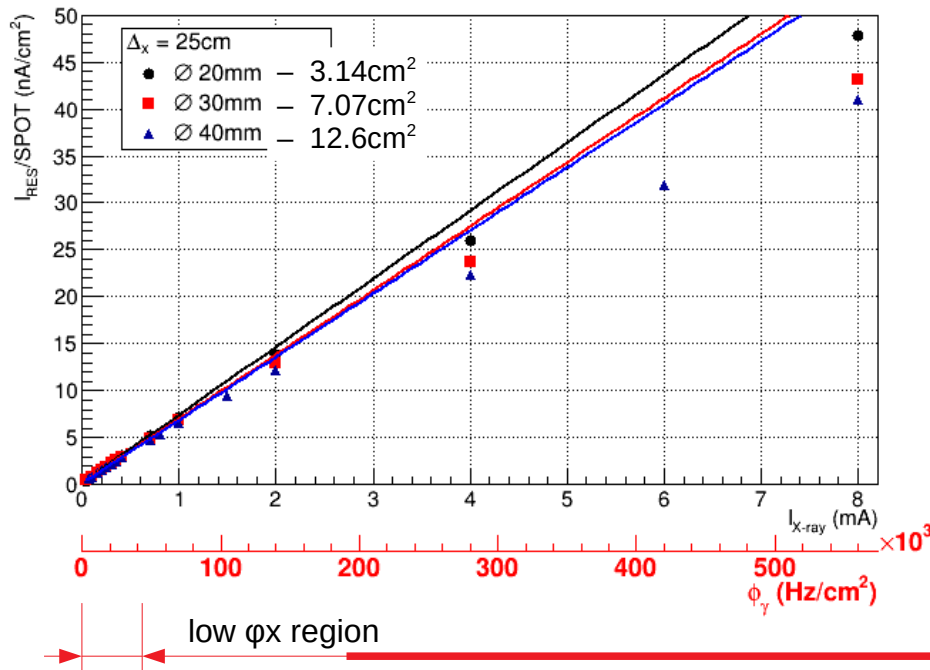
Choice of Pb hole diameters



The use of the Pb shieldings ensures a **nearly uniform X-ray irradiation** over the spot. Using the APV25 it was possible to check the spot dimensions, compatible with the nominal Pb diameters.

Example of data taking

DRL μ -RWELL, $G = 4000$, $\rho = 54 \text{ M}\Omega/\square$, Conductive hole pitch 7mm, $\text{Ar}/\text{CO}_2/\text{CF}_4 - 45/15/40$



Low $I_{x\text{-ray}} \rightarrow$ Linear fit \rightarrow Extrapolations:

$$i_{\text{ext}} = m' \cdot I_{x\text{-ray}} + q' \rightarrow i_{\text{ext}} \text{ extrapolation at high } I_{x\text{-ray}}$$

$$\Phi_{x\text{-ray}} = i_{\text{ext}} / e \cdot N \cdot S \cdot G_0 \rightarrow \Phi_{x\text{-ray}} \text{ extrapolation at high } I_{x\text{-ray}}$$

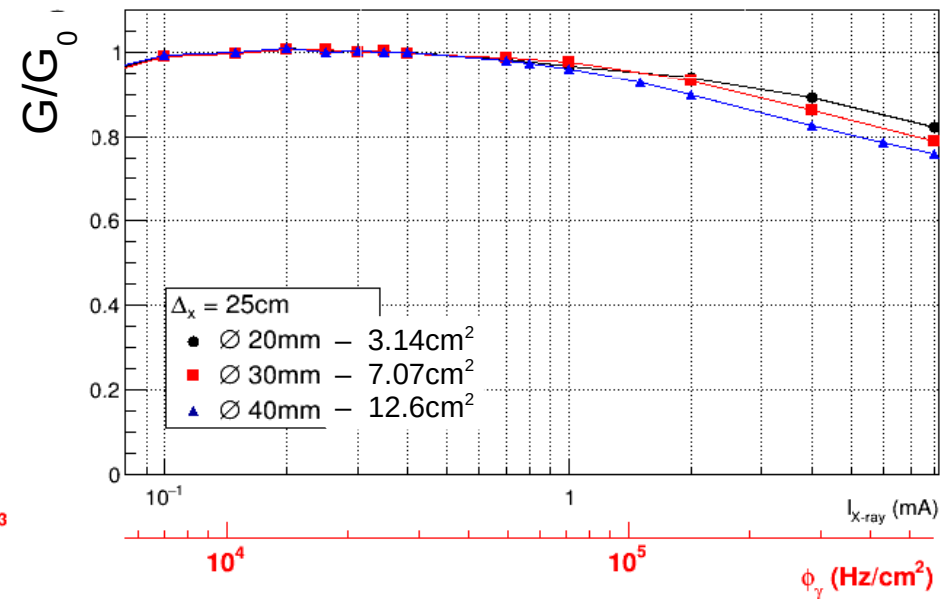
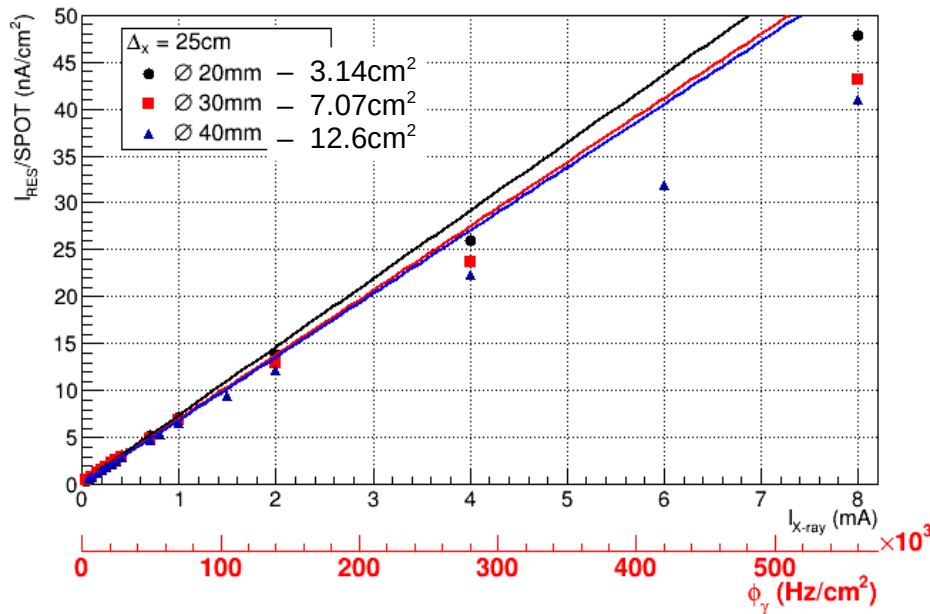
$$G/G_0 = i_{\text{res}} / i_{\text{ext}}$$

Maximum $I_{\text{RES}} @ I_{x\text{-ray}} = 8\text{mA}$:

- $\text{\O}20\text{mm} \rightarrow 150\text{nA}$
- $\text{\O}30\text{mm} \rightarrow 305\text{nA}$
- $\text{\O}40\text{mm} \rightarrow 510\text{nA}$

Example of data taking

DRL μ -RWELL, $G = 4000$, $\rho = 54 \text{ M}\Omega/\square$, Conductive hole pitch 7mm, Ar/CO₂/CF₄ - 45/15/40



Low $I_{x-ray} \rightarrow$ Linear fit \rightarrow Extrapolations:

$$i_{ext} = m' \cdot I_{x-ray} + q' \rightarrow i_{ext} \text{ extrapolation at high } I_{x-ray}$$

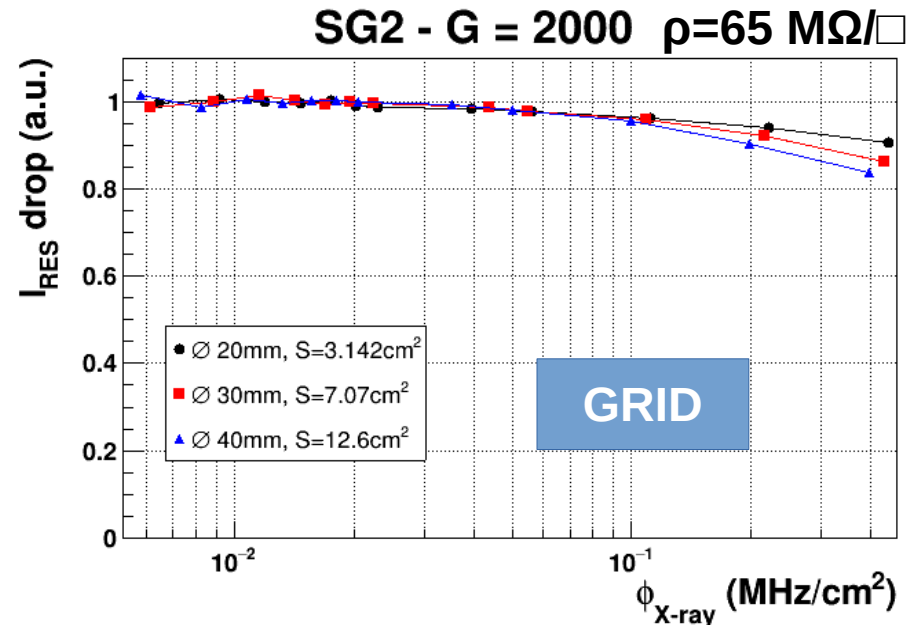
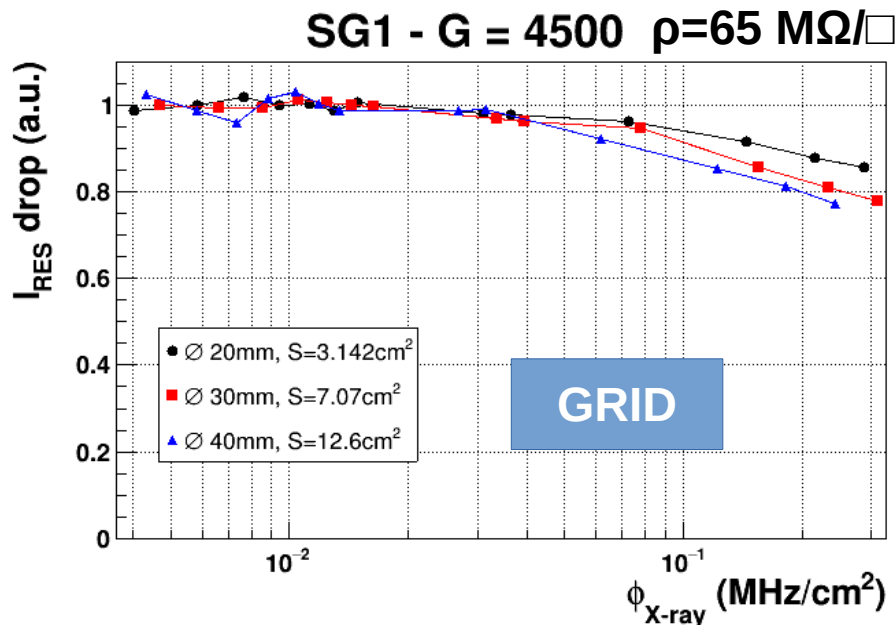
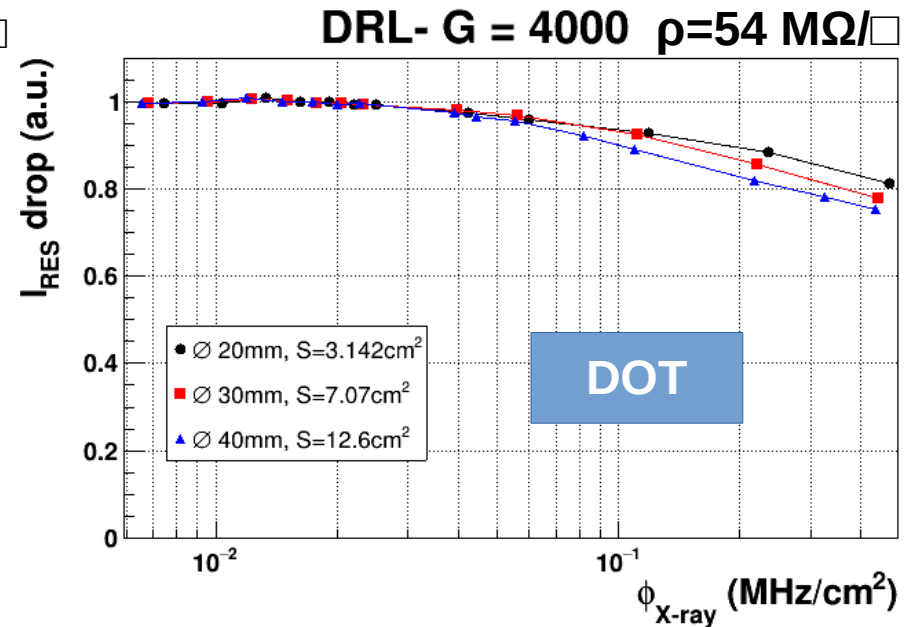
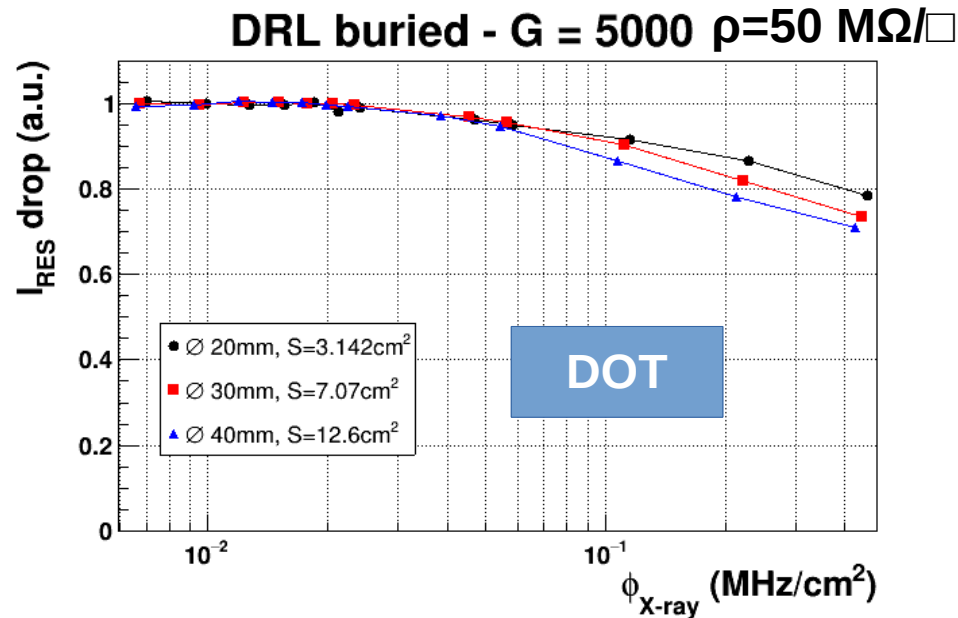
$$\Phi_{x-ray} = i_{ext} / e \cdot N \cdot S \cdot G_0 \rightarrow \phi_{x-ray} \text{ extrapolation at high } I_{x-ray}$$

$$G/G_0 = i_{res} / i_{ext}$$

Maximum I_{RES} @ $I_{x-ray} = 8\text{mA}$:

$\varnothing 20\text{mm} \rightarrow 150\text{nA}$
 $\varnothing 30\text{mm} \rightarrow 305\text{nA}$
 $\varnothing 40\text{mm} \rightarrow 510\text{nA}$

X-ray rate capability for LNF layouts



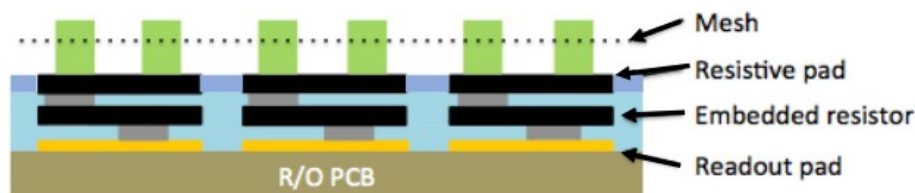
High Rate MicroMegas

Test campaign with X-ray on high rate MicroMegas:
testing different surface resistivity values and
current evacuation schemes.

See M. Iodice
talk 17/02/21

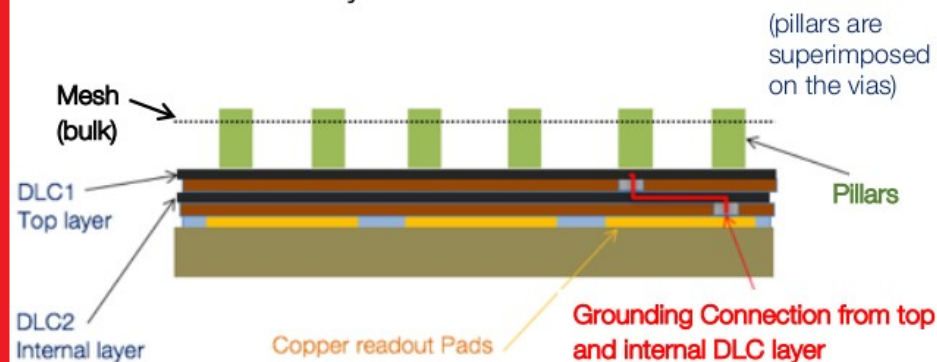
The Double DLC MM has a similar resistive stage than our DRL scheme.

PAD-Patterned resistive layer



- Embedded resistors by Screen-Printing
- Resistive pads by paste filling of photoimaging created vessels
- each pad is totally separated from the others, for the anode, as well as for the resistive part

Double DLC (Diamond Like Carbon) uniform resistive layer

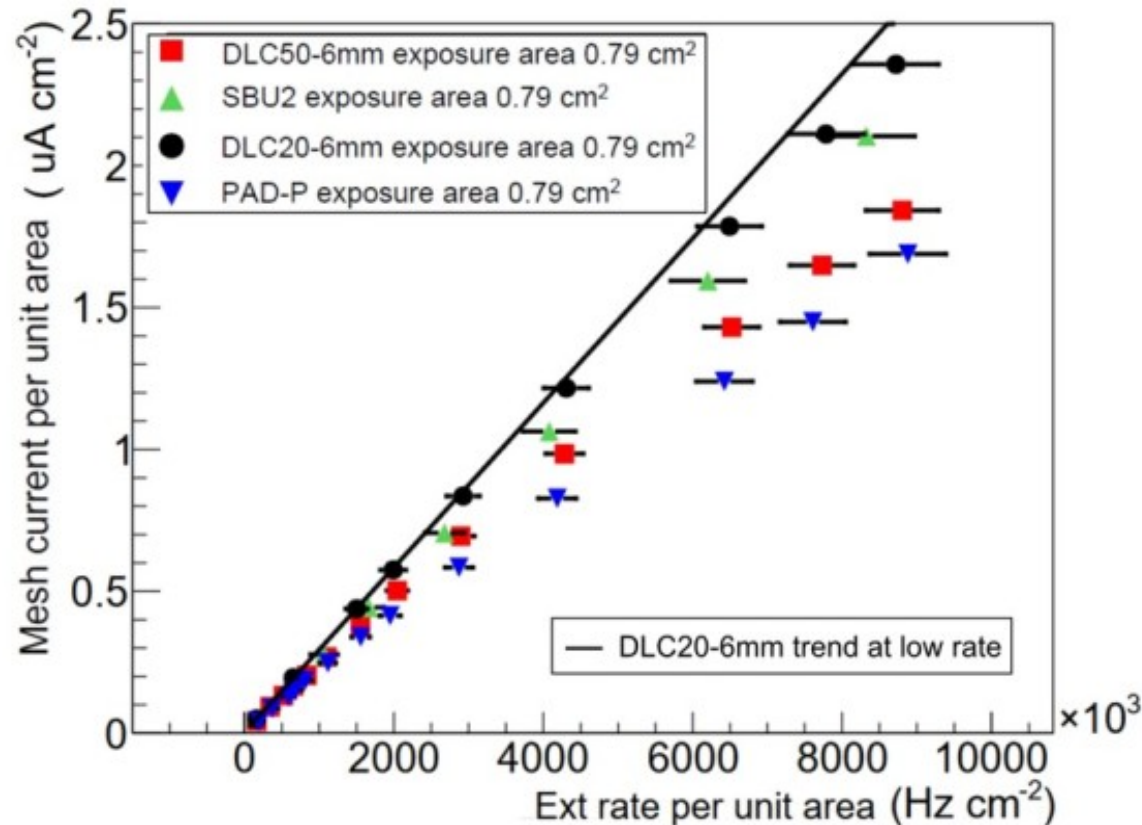


- Same concept of uRWell
(see G.Bencivenni et al. 2015_JINST_10_P02008)
- Double DLC layer with connection vias to ground every "few" mm

DLC20: $20\text{M}\Omega/\square$, DLC50: $50\text{-}70\text{M}\Omega/\square$

High Rate MicroMegas

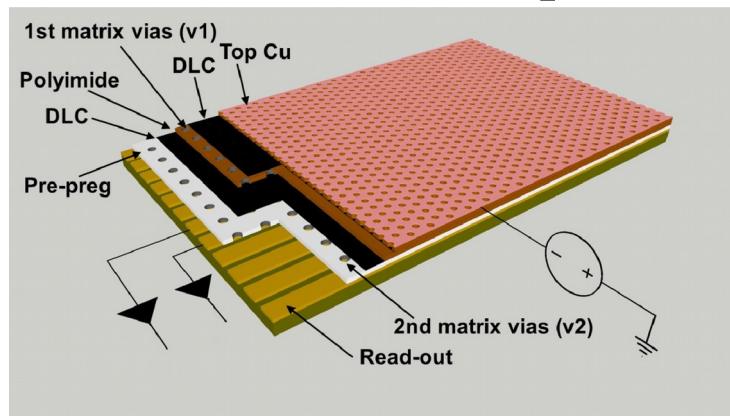
G=6500, gas mixture Ar/CO₂ 93/7



X-ray measurements 8keV.

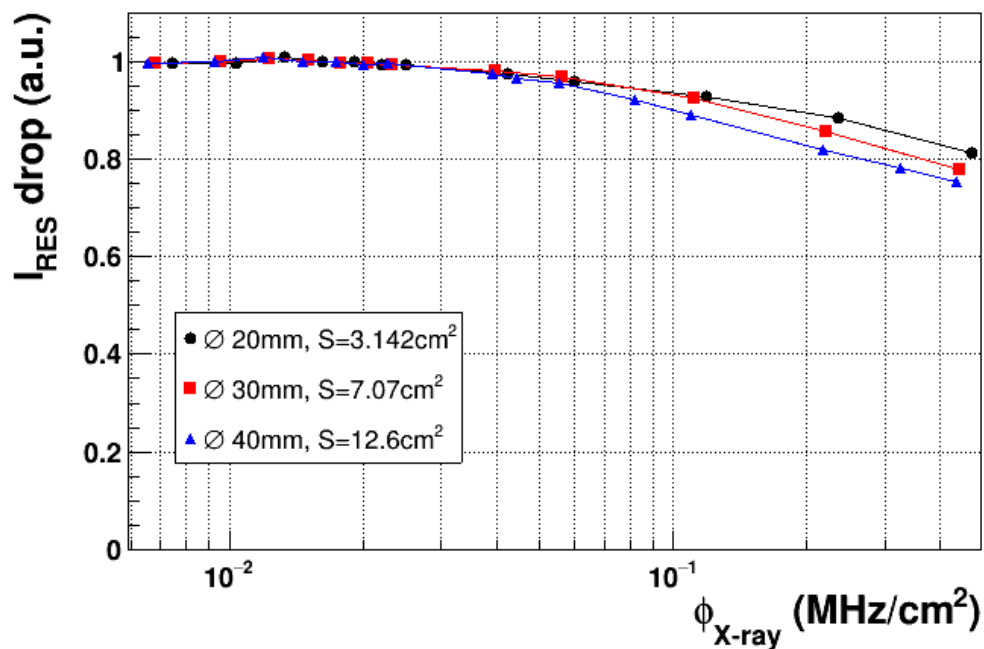
DLC20 shows a better behaviour than **DLC50** and other prototypes.

MM & μ -RWELL: ratecap

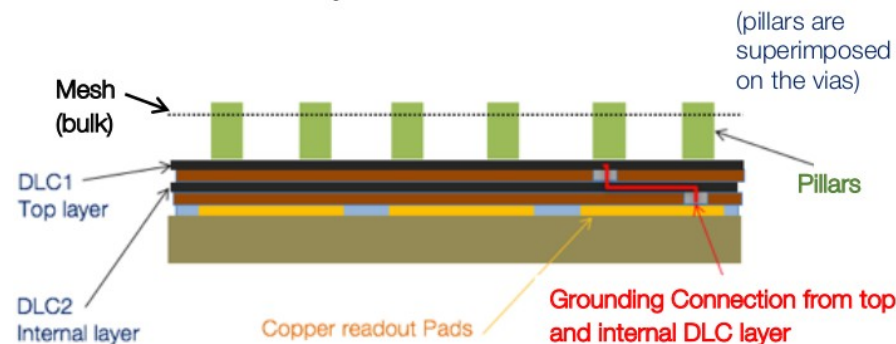


Ar/CO₂/CF₄ – 45/15/40
 X-ray 5.9 keV → N=187 e-l pairs
 Gain = 4000, $\rho=50-70 \text{ M}\Omega/\square$
 Heavy cathode

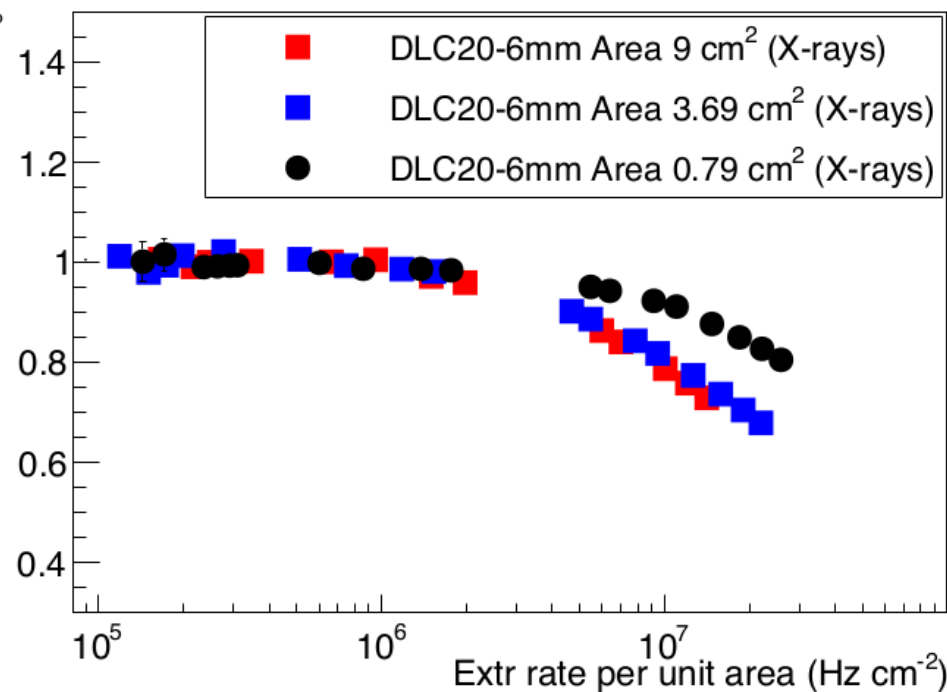
DRL- G = 4000



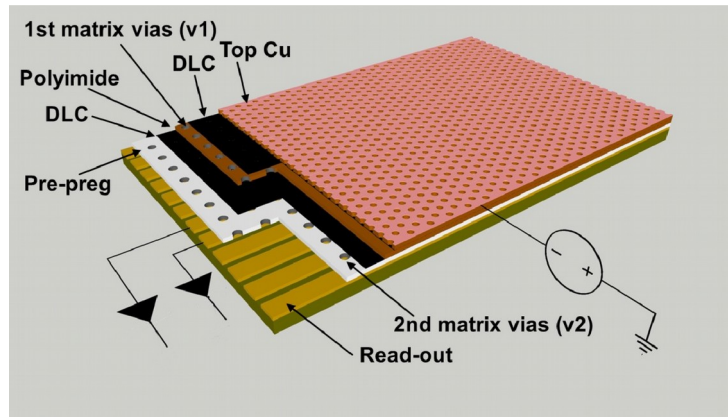
Double **DLC** (Diamond Like Carbon)
 uniform resistive layer



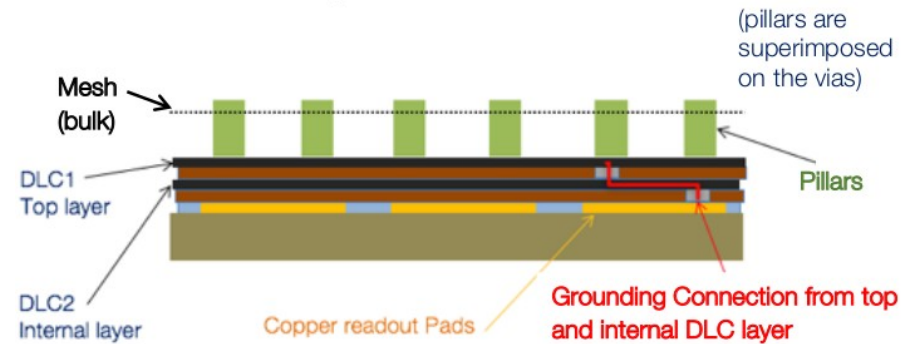
Ar/CO₂ – 97/3
 X-ray 8 keV → N=285 e-l pairs
 Gain = 6500, $\rho=20 \text{ M}\Omega/\square$
 Light cathode



MM & μ -RWELL: ratecap



Double **DLC** (Diamond Like Carbon)
uniform resistive layer



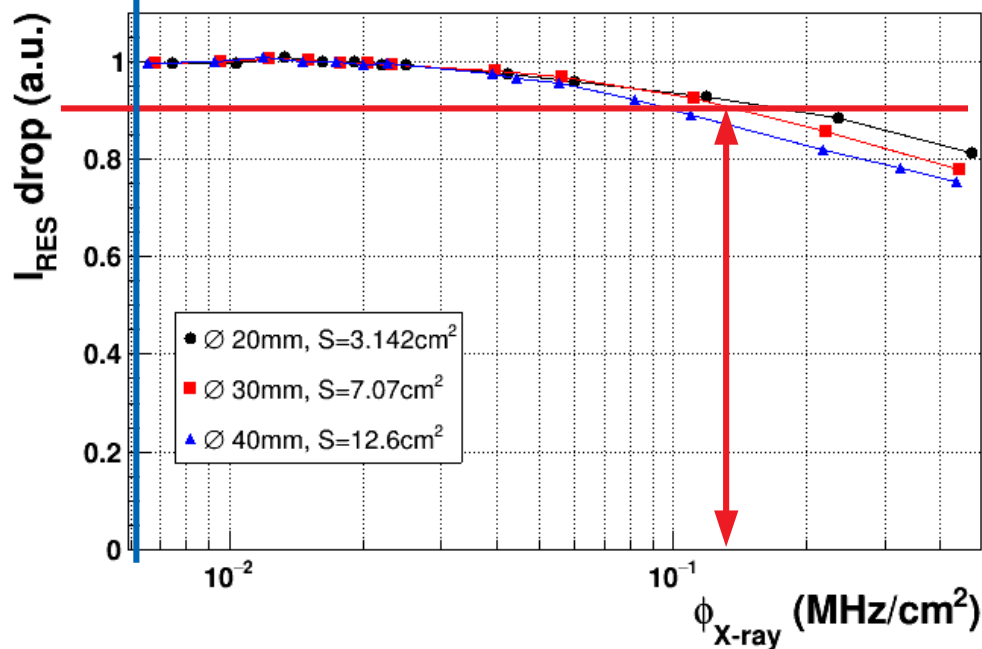
Ar/CO₂/CF₄ – 45/15/40

X-ray 5.9 keV → N=187 e-l pairs

Gain = 4000, $\rho=50-70 \text{ M}\Omega/\square$

Heavy cathode

DRL- G = 4000

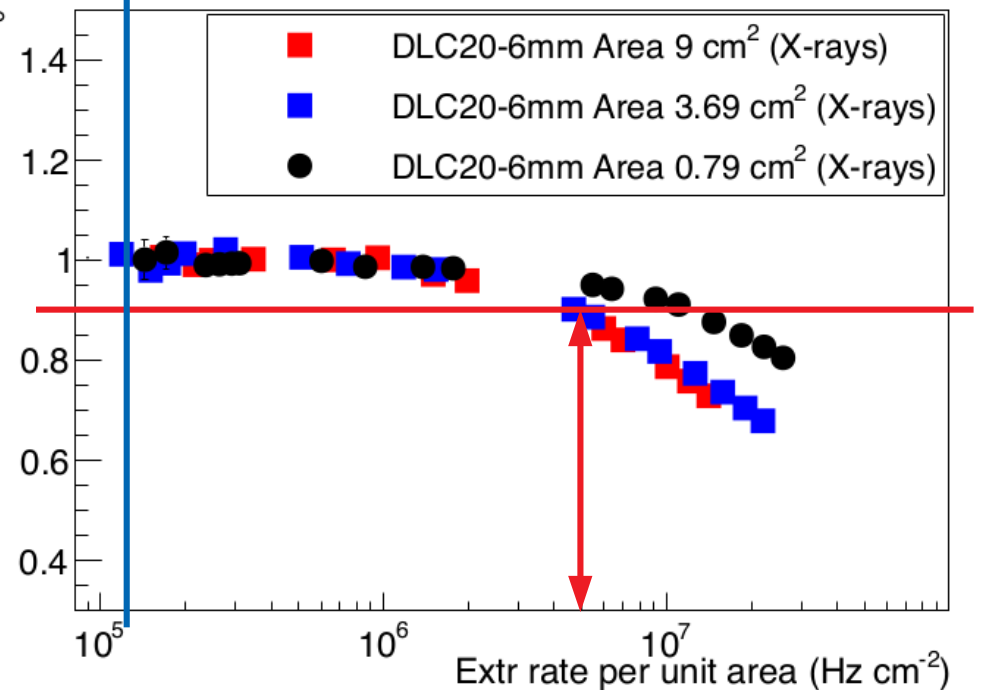


Ar/CO₂ – 97/3

X-ray 8 keV → N=285 e-l pairs

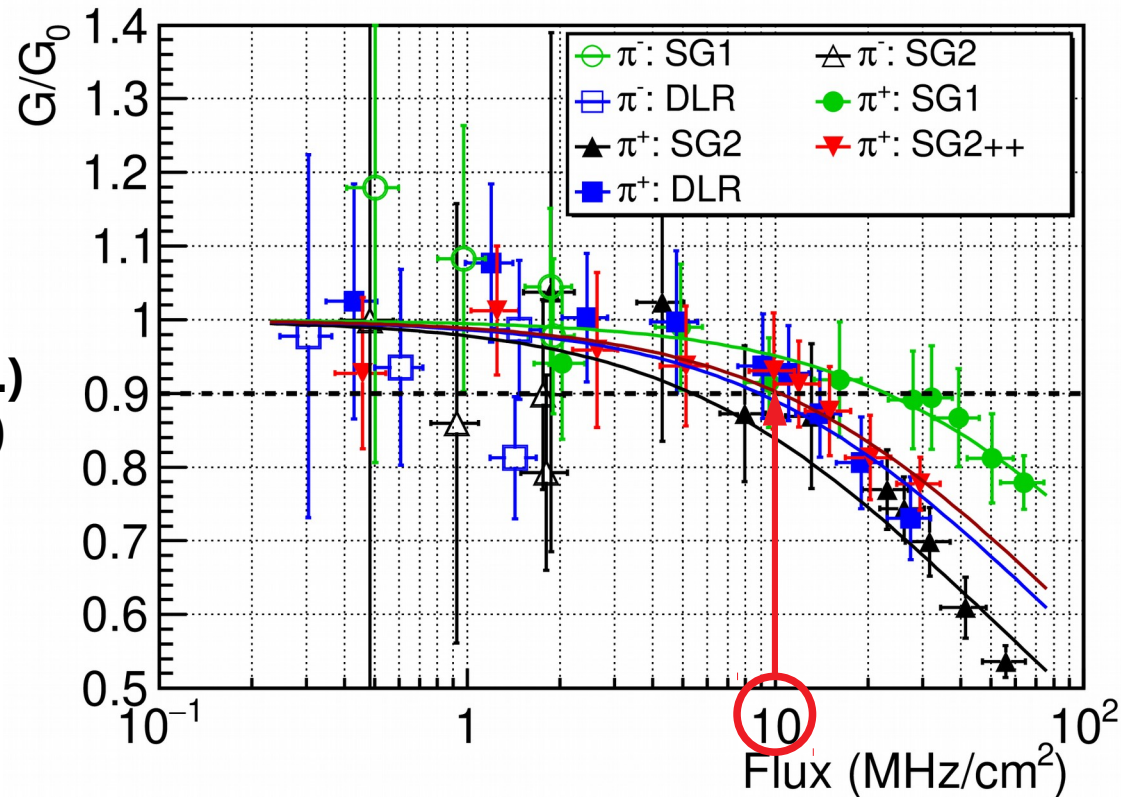
Gain = 6500, $\rho=20 \text{ M}\Omega/\square$

Light cathode



μ -RWELL rate capability @ PSI '18

A larger Rate Capability has been previously measured @ PSI.



Beam conditions:
 π^+ 350 MeV/c (m.i.p.)
spot \varnothing 28mm (6cm²)

$G/G_0 = 90\%$

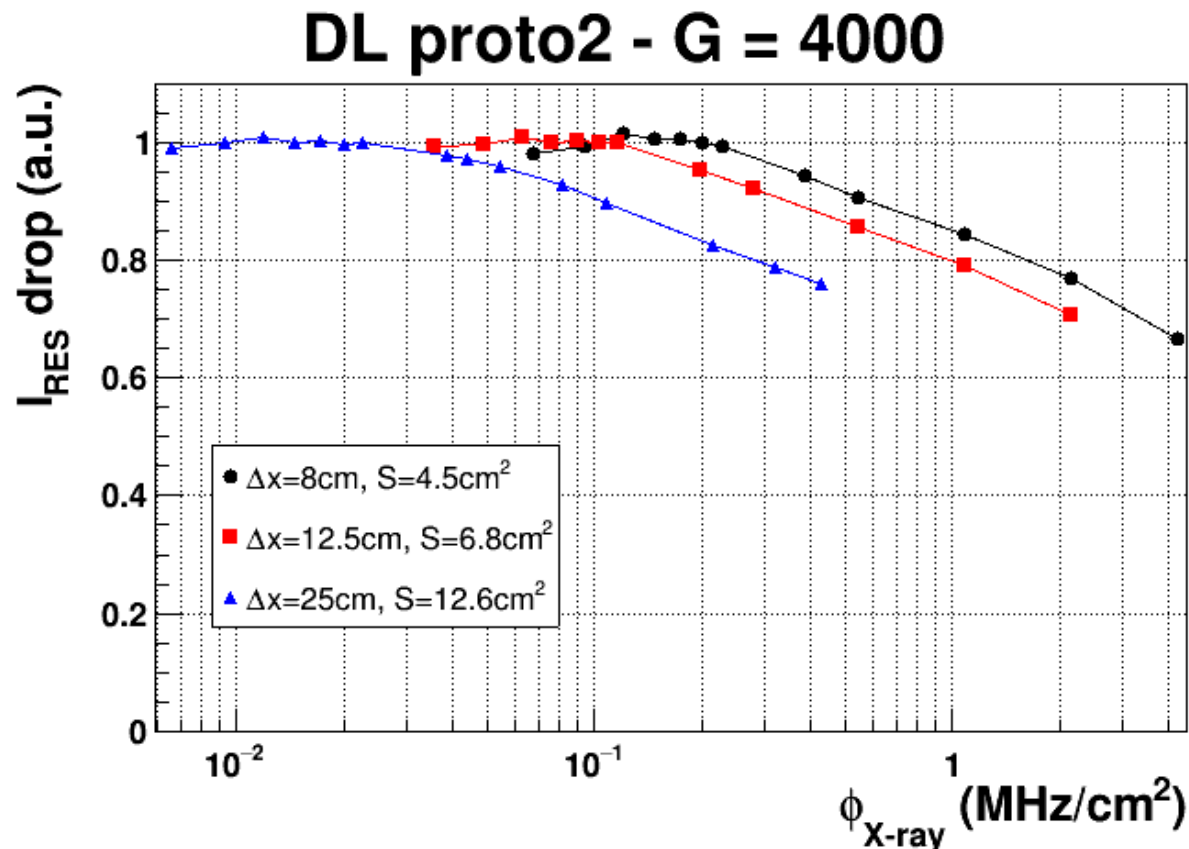
Same chambers used with X-Ray.
GEM detectors used for defining both flux and gain drop.

Rate capability with **m.i.p.** → **10 MHz/cm²**.

Is the extrapolation well done?

Hypothesis: a fit in a flux range where the detector response is not linear lead to a large deviation from the true rate capability.

In order to check this hypothesis we have measured the rate capability at different distances from the X-ray gun. This allows us to explore different flux ranges for the first points.

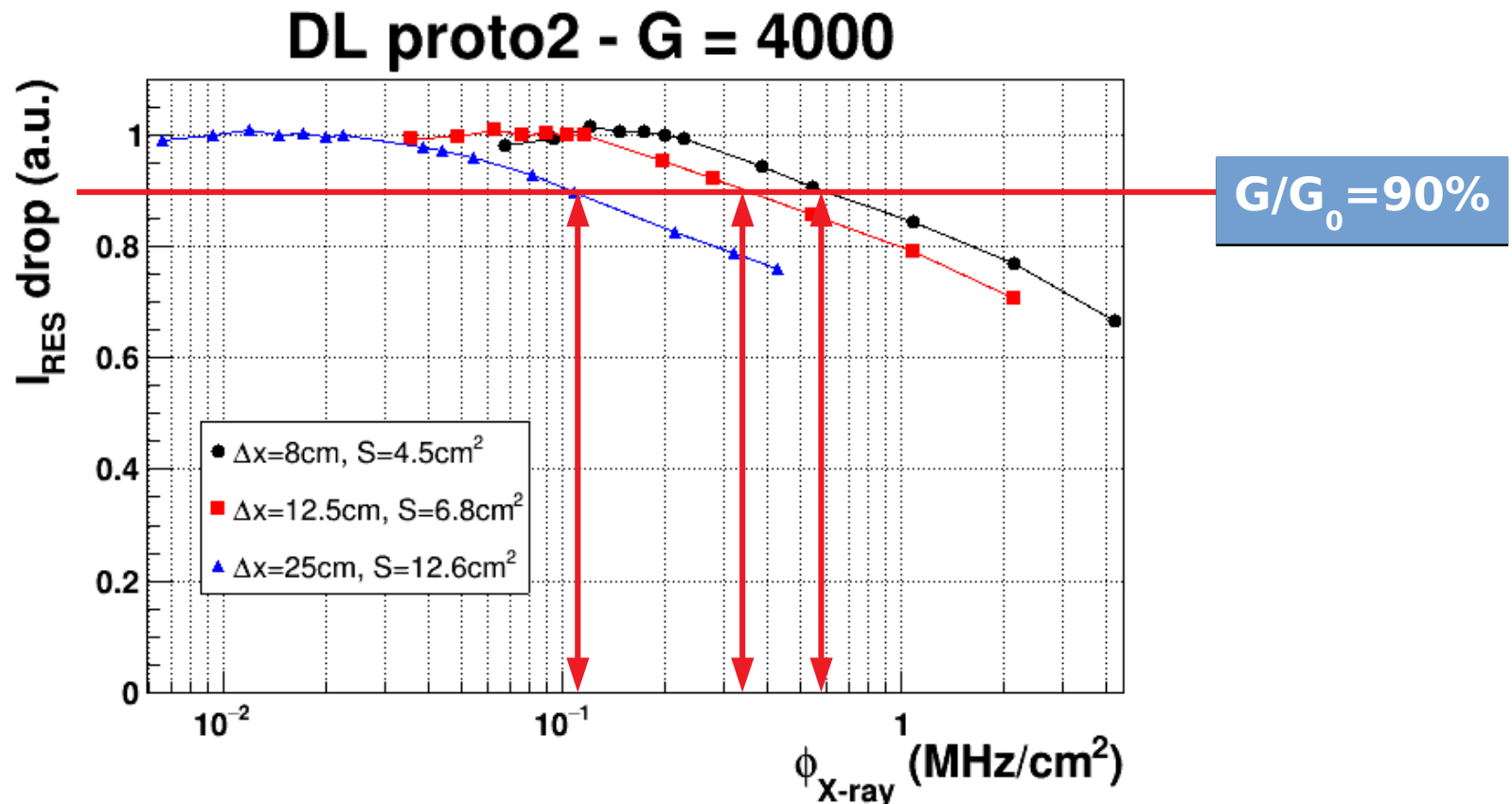


Same detector as before (DRL). The different spot size could not explain the differences among the three curves. **The effect of a wrong extrapolation seems evident.**

Is the extrapolation well done?

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Same detector as before (DRL). The different spot size could not explain the differences among the three curves. **The effect of a wrong extrapolation seems evident.**

Conclusions

Standing the validity of the PSI results:

- No relevant dependence on the spot size for μ -RWELL (grid and dot)
- No relevant dependence on the spot size for MM (dot)
- Extrapolation effect on the rate capability measurement with X-ray

Outlook

- Light cathode for μ -RWELL for X-ray measurements
- A different approach for the extrapolation, based on a global fit of the data
- Due to the spread of resistive detectors in our field, we propose to clearly define a shared method for rate capability measurements inside the resistive CP:
 - spot definition (RMS, FWHM, sigma)
 - G_0 extrapolation
- In this framework LNF will soon host MMM (Mauro's MicroMegas)...
- ... waiting for Zhou Yi

SG1 – PEDDP comparison

SG1 u-RWELL

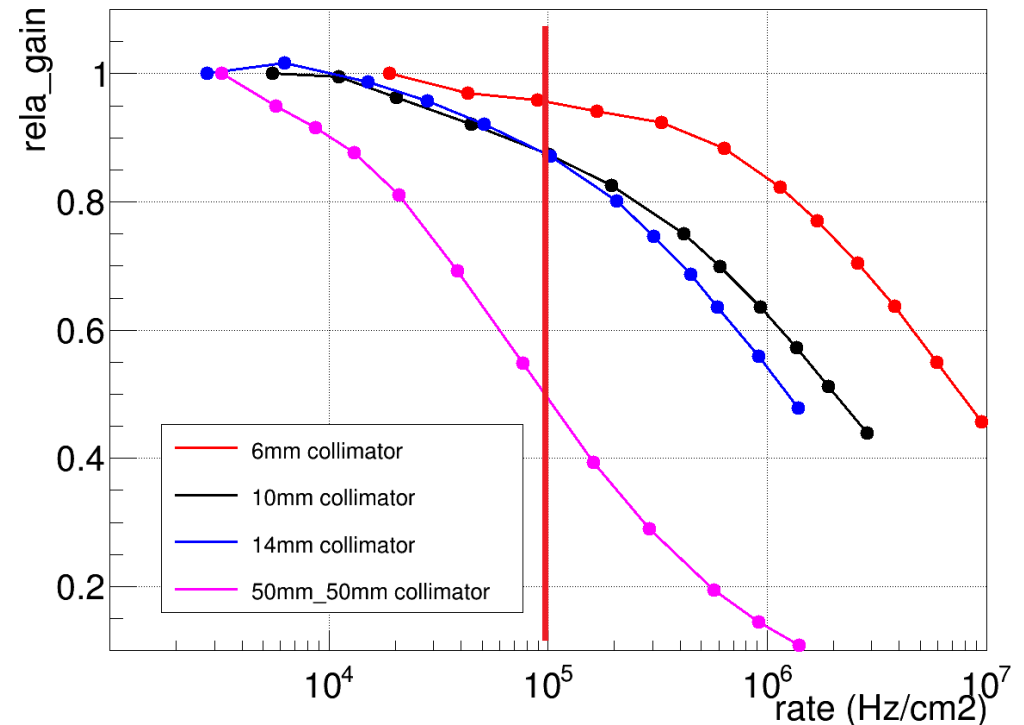
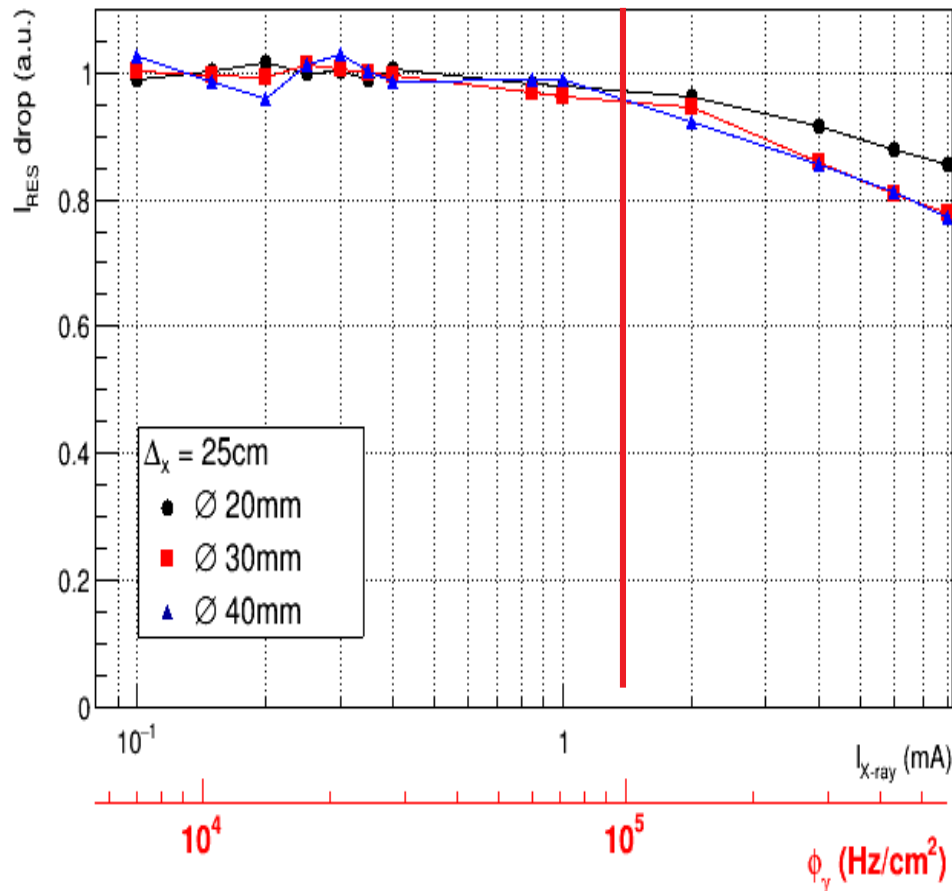
Gain = 4500, $\rho=70 \text{ M}\Omega/\square$

Grid pitch 6mm, dead area 2mm
geom. acceptance 66%

PEDP u-RWELL

Gain = 6500, $\rho=???\text{ M}\Omega/\square$

Conductive hole pitch 5mm



PEDP: Patterning , Etching , Drilling & Plating



PEDP μ RWELL

Conductive hole pitch: 5 mm

Is strip charge evacuation better than dot one?

DL – PEDP comparison

DL u-RWELL

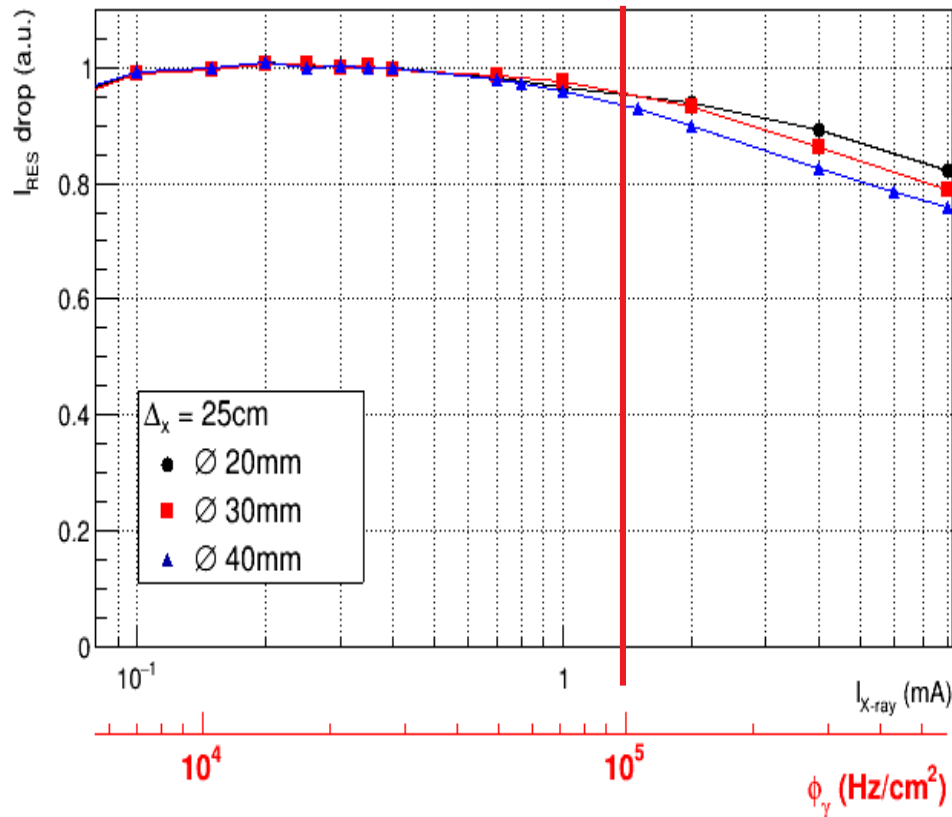
Gain = 4000, $\rho=50-70 \text{ M}\Omega/\square$

Conductive hole pitch 7mm

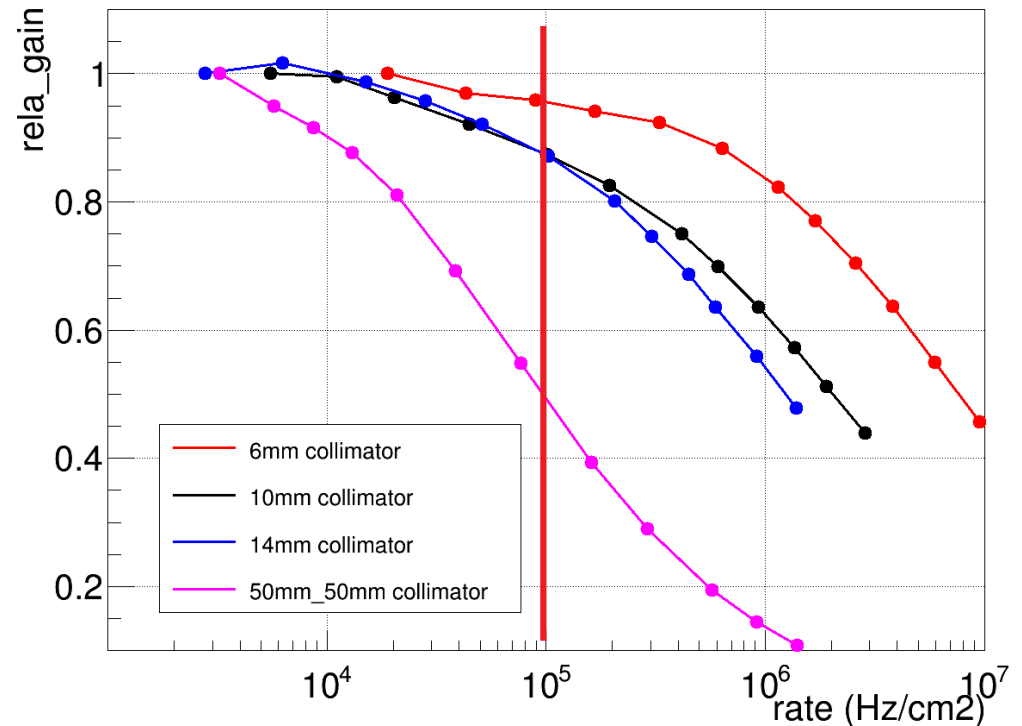
PEDP u-RWELL

Gain = 6500, $\rho=???\text{ M}\Omega/\square$

Conductive hole pitch 5mm



Our DL layout doesn't show any problems.



PEDP: Patterning , Etching , Drilling & Plating



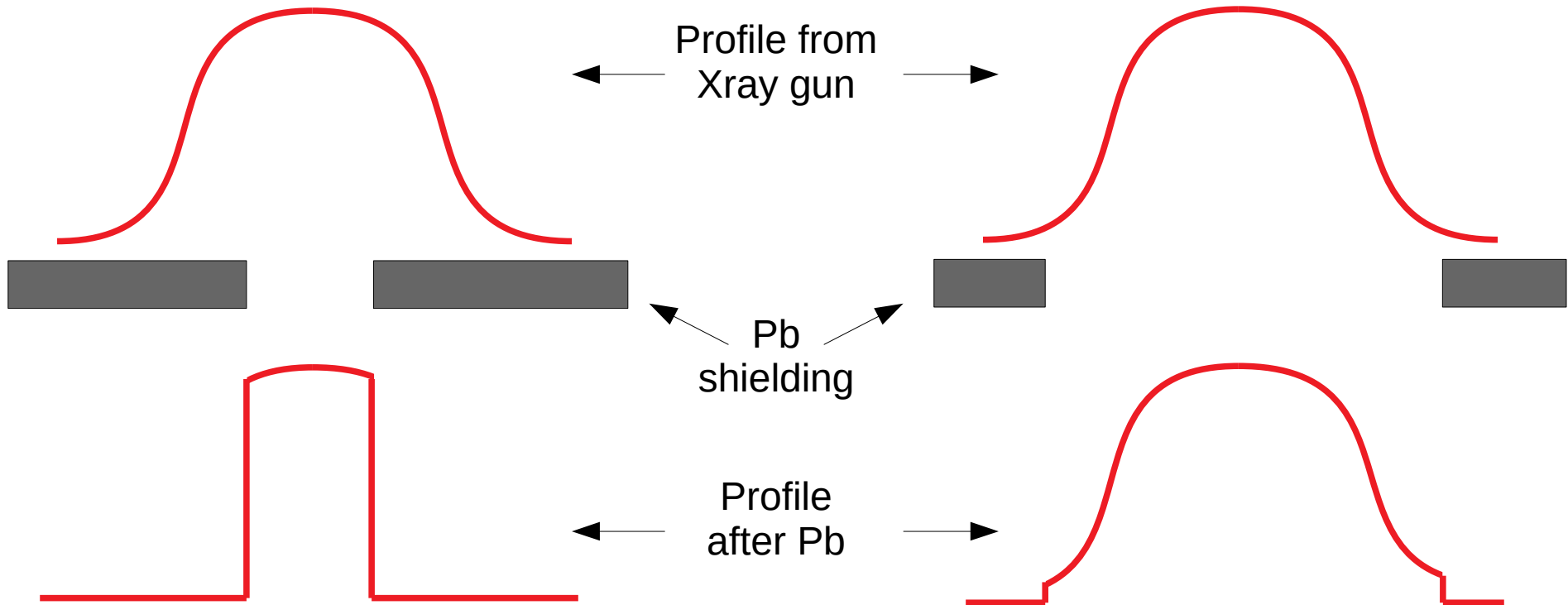
PEDP μ RWELL

Conductive hole pitch: 5 mm

Choice of Pb hole diameters

OPTIMAL Pb HOLES

LARGE Pb HOLES



The use of the Pb shieldings to determine the X-ray spot is effective only if the former is smaller. This condition is a compromise between distance from the Xray gun and the size of the hole. At a given distance and detector gain, and for the lowest possible Xray flux, we measure the current drawn by the detector. **If the ratio current/SPOT wouldn't change we are confident that the beam is homogeneous.**

In the end we choose $\Delta x=25\text{cm}$ and $\text{Ø} = 20,30,40\text{mm}$

$$\frac{G_k}{G_{0,k}} = \frac{i_k}{eNS\phi_k} \frac{eNS\phi_{0,k}}{i_{0,k}} = \frac{i_k}{i_{0,k}} \frac{\phi_{0,k}}{\phi_k}$$

G/G_0 definition for the k^{th} μ -RWELL detector.

$$\frac{G_{GEM}}{G_{0,GEM}} = \frac{i_{GEM}}{eNS\phi_{GEM}} \frac{eNS\phi_{0,GEM}}{i_{0,GEM}} = \frac{i_{GEM}}{i_{0,GEM}} \frac{\phi_{0,GEM}}{\phi_{GEM}} = 1$$

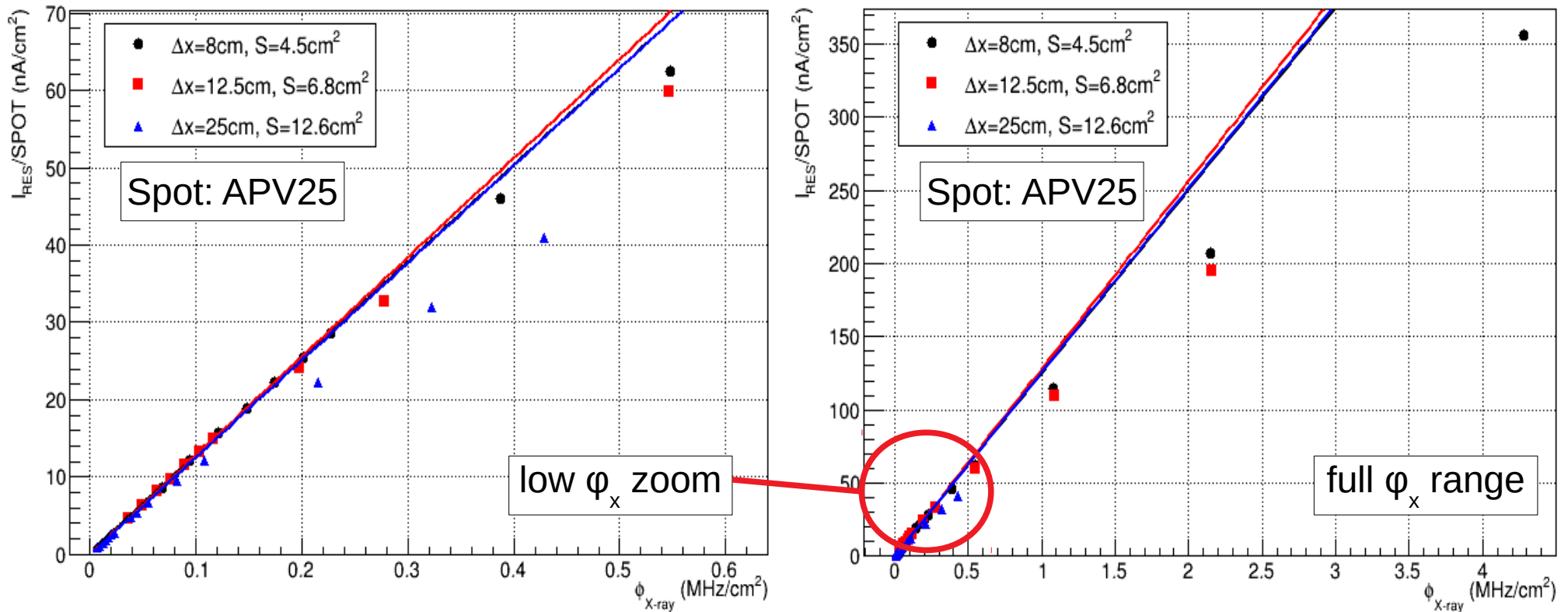
$$\frac{\phi_{0,GEM}}{\phi_{GEM}} = \frac{i_{0,GEM}}{i_{GEM}}$$

It is possible to use a GEM to measure the rate capability, under two assumptions:

- The GEM doesn't suffer rate effects ($G_{GEM}/G_{0,GEM} = 1$)
- The impinging flux is the same on the GEM and the μ -RWELL

$$\frac{G_k}{G_{0,k}} = \frac{i_k}{i_{0,k}} \frac{\phi_{0,k}}{\phi_k} = \frac{i_k}{i_{0,k}} \frac{i_{0,GEM}}{i_{GEM}} = \mathcal{N} \frac{i_k}{i_{GEM}}$$

Is the normalization well done?



This measurement seems to be affected by the normalization done at low flux from which we extrapolate: the reference gain (G_0) and the X-ray flux axis.

In order to check this hypothesis we have measured the rate capability at different distances from the X-ray gun. This allows us to explore different flux ranges for the first points.

The linear fit must be done for a flux range in which the detector is not affected by a gain drop. Our hypothesis is that a fit in a flux range in which the detector response is not really linear could lead to a large deviation from the true rate capability.